



1200V /40A Trench Field Stop IGBT

- High breakdown voltage to 1200V for improved reliability
- Trench-Stop Technology offering :
 - High speed switching
 - High ruggedness, temperature stable
 - Short circuit withstand time – 10μs
 - Low V_{CEsat}
 - Easy parallel switching capability due to positive temperature coefficient in V_{CEsat}
- Enhanced avalanche capability

- Uninterruptible Power Supplies
- Solar inverter
- Welding
- PFC applications

Product	Package	Packaging
YGW40N120F1A1	TO247	Tube

Parameter	Symbol	Value	Unit
Collector-Emitter Breakdown Voltage	V_{CE}	1200	V
DC collector current, limited by T_{jmax} $T_C = 25^\circ C$ $T_C = 100^\circ C$	I_C	80 40	A
Diode Forward current, limited by T_{jmax} $T_C = 25^\circ C$ $T_C = 100^\circ C$	I_F	80 40	A
Continuous Gate-emitter voltage	V_{GE}	± 20	V
Transient Gate-emitter voltage	V_{GE}	± 30	V
Turn off safe operating area $V_{CE} = 1200V$, $T_j = 150^\circ C$	-	160	A
Pulsed Collector Current, $V_{GE} = 15V$, t_p limited by T_{jmax}	I_{CM}	160	A
Diode Pulsed Current, t_p limited by T_{jmax}	I_{Fpuls}	160	A
Short Circuit Withstand Time, $V_{GE} = 15V$, $V_{CE} = 600V$	T_{sc}	10	μs
Power dissipation, $T_j = 25^\circ C$	P_{tot}	417	W
Operating junction temperature	T_j	-40...+150	$^\circ C$
Storage temperature	T_s	-55...+150	$^\circ C$
Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s	-	260	$^\circ C$

Parameter	Symbol	Max. Value	Unit
IGBT thermal resistance, junction - case	$R(j-c)$	0.3	K/W
Diode thermal resistance, junction - case	$R(j-c)$	≤ 0.7	K/W
Thermal resistance, junction - ambient	$R(j-a)$	40	K/W

($T_j = 25^\circ\text{C}$ unless otherwise specified) :

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Collector-Emitter breakdown voltage	BV_{CES}	$V_{GE}=0V, I_C=250\mu A$	1200	1300	-	V
Gate threshold voltage	$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C=250\mu A$	5.1	5.8	6.4	V
Collector-Emitter Saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=40A$ $T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$	- -	2.0 2.5	2.5 -	V
Zero gate voltage collector current	I_{CES}	$V_{CE} = 1200V, V_{GE} = 0V$ $T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$	- -	- -	10 2500	μA
Gate-emitter leakage current	I_{GES}	$V_{CE} = 0V, V_{GE} = \pm 20V$	-	-	100	nA
Transconductance	g_{fs}	$V_{CE}=20V, I_C=15A$	-	15	-	S

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Input capacitance	C_{ies}	$V_{CE} = 25V, V_{GE} = 0V,$ $f = 1\text{MHz}$	-	4400	-	pF
Output capacitance	C_{oes}		-	180	-	
Reverse transfer capacitance	C_{res}		-	100	-	
Gate charge	Q_G	$V_{CC} = 960V, I_C = 40A,$ $V_{GE} = 15V$	-	270	-	nC
Short circuit collector current	$I_{C(SC)}$	$V_{GE}=15V, t_{SC} 10\mu s$ $V_{CC}=600V,$ $T_{j, start}=25^\circ\text{C}$	-	240	-	A

Parameter						
Turn-on delay time	$t_{d(on)}$	$V_{CC} = 600V, I_C = 40A,$ $V_{GE} = 0/15V,$ $R_g = 12\Omega$	-	60	-	ns
Rise time	t_r		-	27	-	ns
Turn-on energy	E_{on}		-	2.9	-	mJ
Turn-off delay time	$t_{d(off)}$		-	230	-	ns
Fall time	t_f		-	70	-	ns
Turn-off energy	E_{off}		-	0.8	-	mJ

Fig. 5 Output characteristics



Fig. 6 Saturation voltage characteristics

Fig. 7 Switching times vs. gate resistor

Fig. 8 Switching times vs. collector current



